Figure 1

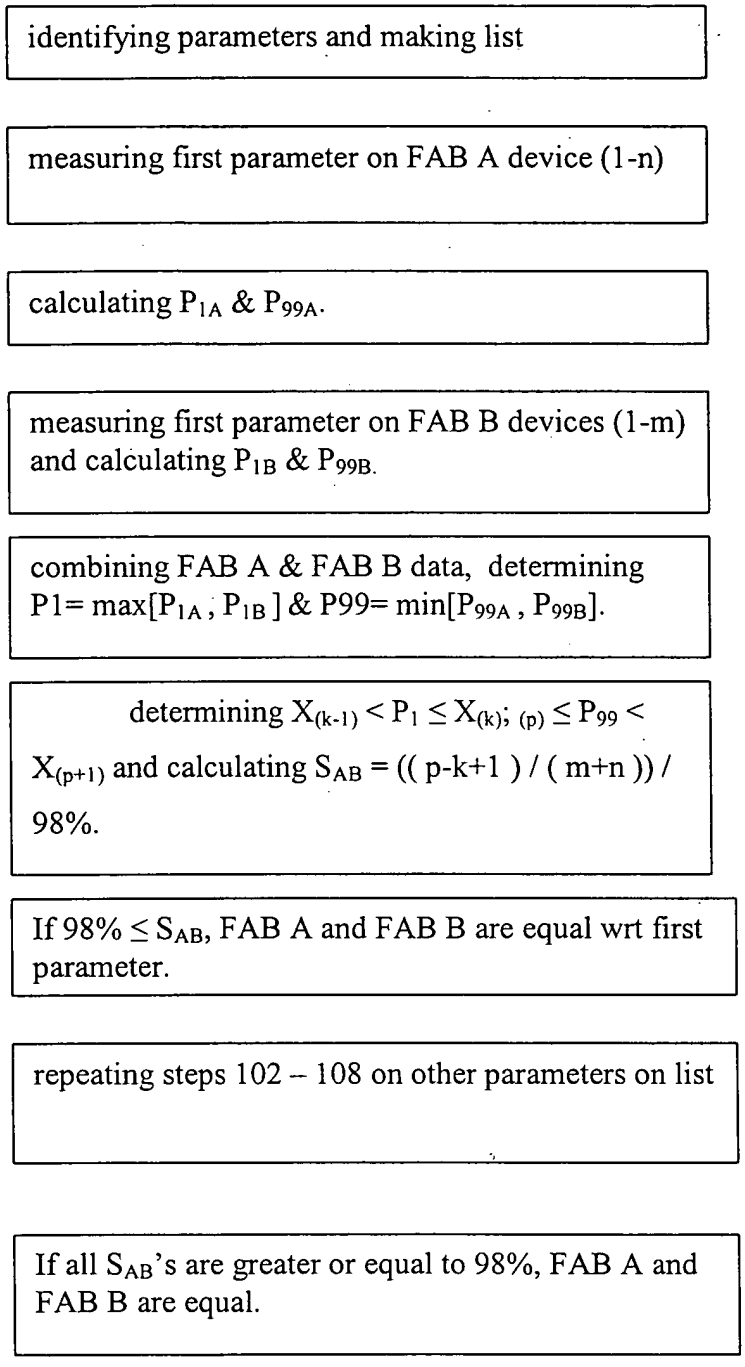
identifying parameters and making list
measuring first parameter on FAB A device (1-n)
calculating P_{1A} & P_{99A}.
measuring first parameter on FAB B devices (1-m) and calculating P_{1B} & P_{99B}.
combining FAB A & FAB B data, determining P1= max[P_{1A} , P_{1B}] & P99= min[P_{99A} , P_{99B}].
determining $X_{(k-1)} < P_1 \leq X_{(k)}$; $_{(p)} \leq P_{99} < X_{(p+1)}$ and calculating S_{AB} = ((p-k+1) / (m+n)) / 98%.
If 98% $\leq S_{AB}$, FAB A and FAB B are equal wrt first parameter.
repeating steps 102 -- 108 on other parameters on list
If all S_{AB}'s are greater or equal to 98%, FAB A and FAB B are equal.

Figure 2

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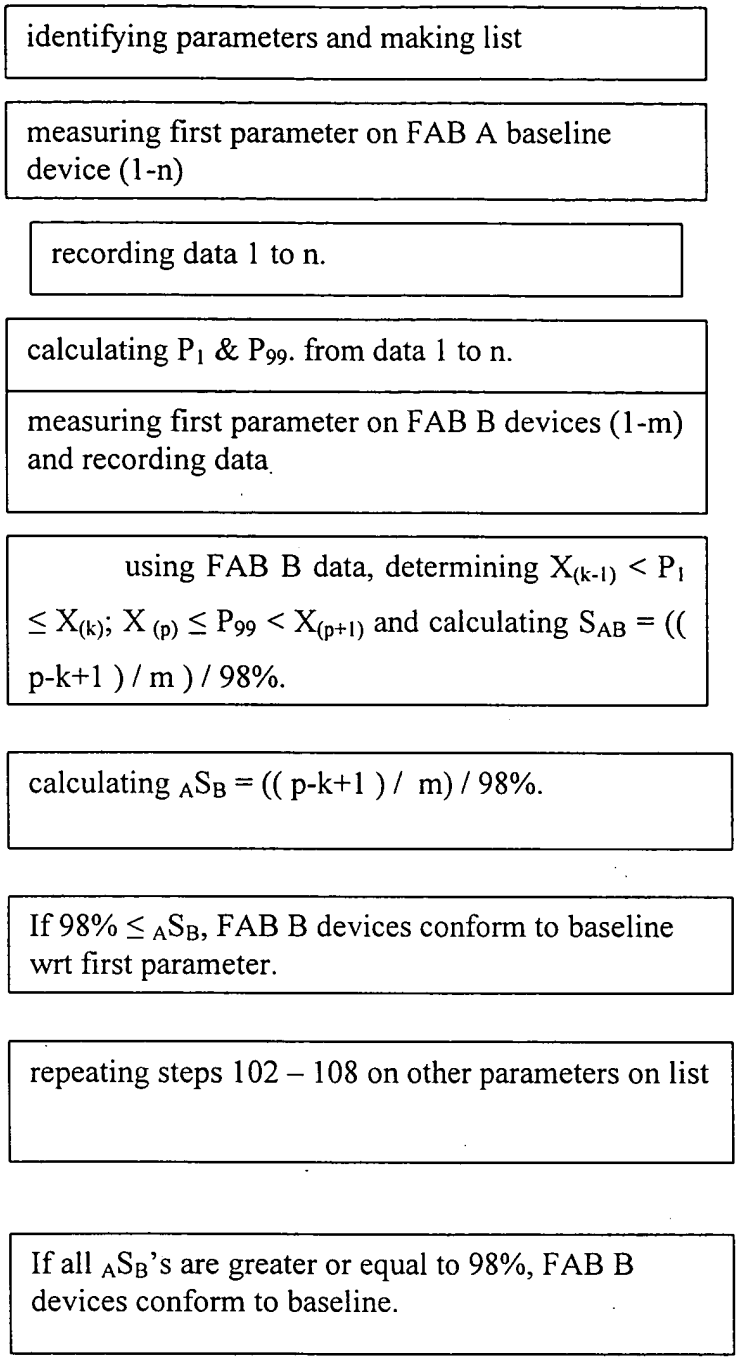

Figure 3

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identifying parameters and making list

measuring first parameter on FAB A device (1-n)

recording FAB A data (1-n)

arranging FAB A data in arrayA.

Inserting pre-determined limits C and D into array and determining $X_{(k-1)} < C \leq X_{(k)}$; $_{(p)} \leq D < X_{(p+1)}$

calculating $_{CD}S_A = ((p-k+1) / (n)) / 98\%$.

If $98\% \leq {}_{CD}S_A$, FAB A devices conform to pre-determined limit wrt first parameter.

repeating steps 302 – 308 on other parameters on list

If all $_{CD}S_A$'s are greater or equal to 98%, FAB A devices conform to pre-determined limit in total